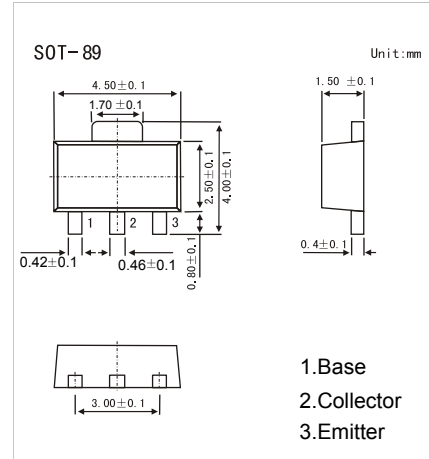


**PNP Transistors**

**2SA1417**

■ Features

- Adoption of FBET, MBIT Processes
- High Breakdown Voltage and Large Current Capacity
- Complementary to 2SC3647



■ Absolute Maximum Ratings  $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Collector - Base Voltage	$V_{CB0}$	-120	V
Collector - Emitter Voltage	$V_{CE0}$	-100	
Emitter - Base Voltage	$V_{EB0}$	-6	
Collector Current - Continuous	$I_c$	-2	A
Collector Current - Pulsed	$I_{CP}$	-3	
Collector Power Dissipation	$P_c$	500	mW
Junction Temperature	$T_J$	150	$^\circ\text{C}$
Storage Temperature range	$T_{stg}$	-55 to 150	

■ Electrical Characteristics  $T_a = 25^\circ\text{C}$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Collector-base breakdown voltage	$V_{CB0}$	$I_c = -100 \mu\text{A}, I_E = 0$	-120			V
Collector-emitter breakdown voltage	$V_{CE0}$	$I_c = -1 \text{mA}, R_{BE} = \infty$	-100			
Emitter - base breakdown voltage	$V_{EB0}$	$I_E = -100 \mu\text{A}, I_c = 0$	-6			
Collector-base cut-off current	$I_{CB0}$	$V_{CB} = -100 \text{V}, I_E = 0$			-0.1	$\mu\text{A}$
Emitter cut-off current	$I_{EB0}$	$V_{EB} = -4\text{V}, I_c = 0$			-0.1	
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_c = -1\text{A}, I_B = -100\text{mA}$		-0.22	-0.6	V
Base - emitter saturation voltage	$V_{BE(sat)}$	$I_c = -1\text{A}, I_B = -100\text{mA}$		-0.85	-1.2	
DC current gain	$h_{FE}$	$V_{CE} = -5\text{V}, I_c = -100\text{mA}$	100		400	
Turn-on time	$t_{on}$	See Test Circuit.		80		ns
Storage time	$t_s$			750		
Fall time	$t_f$			40		
Output capacitance	$C_{ob}$	$V_{CB} = -10\text{V}, I_E = 0, f = 1\text{MHz}$		25		$\mu\text{F}$
Transition frequency	$f_T$	$V_{CE} = -10\text{V}, I_E = -100\text{mA}$		120		MHz

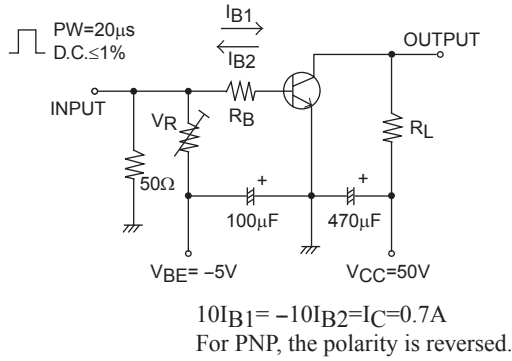
■ Classification of  $h_{FE}$

Marking	ACR*	ACS*	ACT*
Range	100-200	140-280	200-400

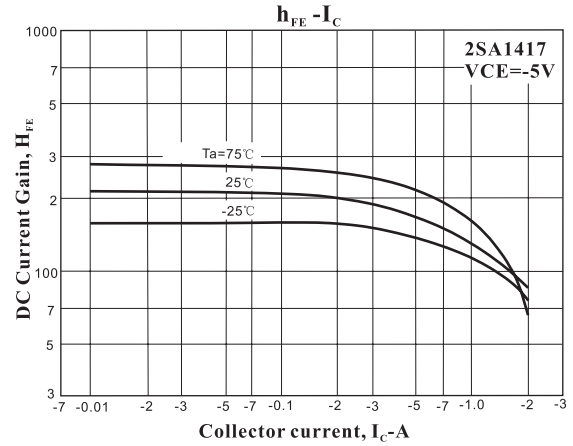
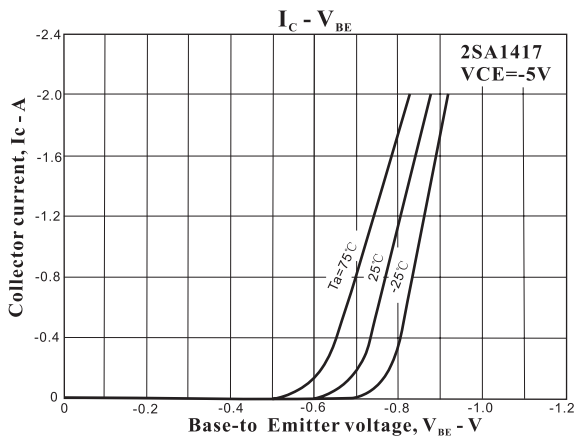
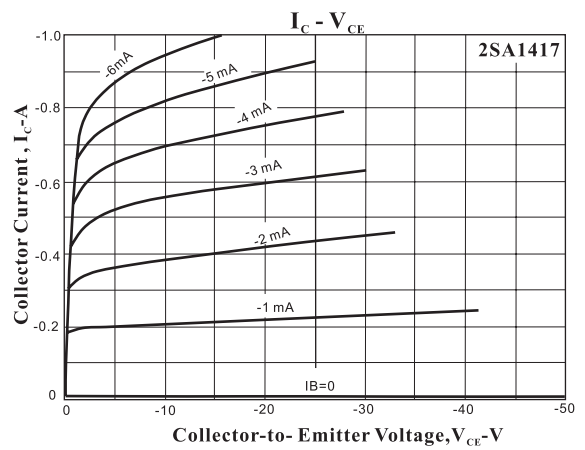
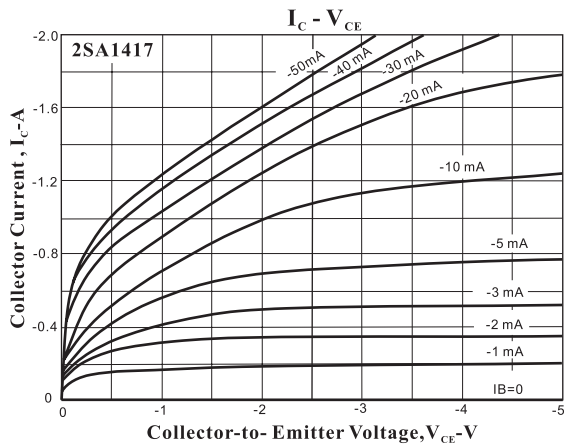
**PNP Transistors**

**2SA1417**

■ Test Circuit



■ Typical Characteristics



## PNP Transistors

### 2SA1417

■ Typical Characteristics

